

<b>Notice of References Cited</b>	Application/Control No. 09/708,722	Applicant(s)/Patent Under Reexamination JOURDAN ET AL.	
	Examiner Aimee J. Li	Art Unit 2183	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,073,213 A	06-2000	Peled et al.	711/125
*	B	US-6,418,530 B2	07-2002	Hsu et al.	712/237
*	C	US-2002/0104075 A1	08-2002	BALA et al.	717/136
*	D	US-6,578,138 B1	06-2003	Kyker et al.	712/241
*	E	US-6,594,734 B1	07-2003	Kyker et al.	711/146
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Rotenberg, Eric; Bennet, Steve; Smith, James E. "A Trace Cache Microarchitecture and Evaluation". IEEE ©1999. Pages 111-120.
	V	Patel, Sanjay Jeram; Friendly, Daniel Holmes; Patt, Yale N. "Critical Issues Regarding the Trace Cache Fetch Mechanism". ©1997. Pages 1-33.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.